Infineon Technologies - XMC1202T016X0032ABXUMA1 Datasheet

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	11
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 11x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-16-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1202t016x0032abxuma1

XMC™1200 AB-Step

Microcontroller Series
for Industrial Applications

XMC™1000 Family

ARM® Cortex®-M0
32-bit processor core

Data Sheet

V1.7 2016-08

Microcontrollers

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Table 3 ADC Channels [1)]

Package	VADC0 G0	VADC0 G1
PG-TSSOP-16	CH0..CH5	CH0..CH4
PG-TSSOP-28	CH0..CH7	CH0 .. CH4, CH7
PG-TSSOP-38	CH0..CH7	CH0..CH7
PG-VQFN-24	CH0..CH7	CH0..CH4
PG-VQFN-40	CH0..CH7	CH1, CH5 .. CH7

1) Some pins in a package may be connected to more than one channel. For the detailed mapping see the Port I/O Function table.

1.4 Chip Identification Number

The Chip Identification Number allows software to identify the marking. It is a 8 words value with the most significant 7 words stored in Flash configuration sector 0 (CS0) at address location : 1000 0F00$_H$ (MSB) - 1000 0F1B$_H$ (LSB). The least significant word and most significant word of the Chip Identification Number are the value of registers DBGROMID and IDCHIP, respectively.

Table 4 XMC1200 Chip Identification Number

Derivative	Value	Marking
XMC1201-T028F0016	00012022 01CF00FF 00001FF7 00006000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1201-T028F0032	00012022 01CF00FF 00001FF7 00006000 00000C00 00001000 00009000 201ED083$_H$	AB
XMC1201-T038F0016	00012012 01CF00FF 00001FF7 00006000 00000C00 00001000 00005000 201ED083$_H$	AB
XMC1201-T038F0032	00012012 01CF00FF 00001FF7 00006000 00000C00 00001000 00009000 201ED083$_H$	AB
XMC1201-T038F0064	00012012 01CF00FF 00001FF7 00006000 00000C00 00001000 00011000 201ED083$_H$	AB
XMC1201-T038F0128	00012012 01CF00FF 00001FF7 00006000 00000C00 00001000 00021000 201ED083$_H$	AB
XMC1201-T038F0200	00012012 01CF00FF 00001FF7 00006000 00000C00 00001000 00033000 201ED083$_H$	AB
XMC1200-T038F0200	00012012 01CF00FF 00001FF7 0000E000 00000C00 00001000 00033000 201ED083$_H$	AB

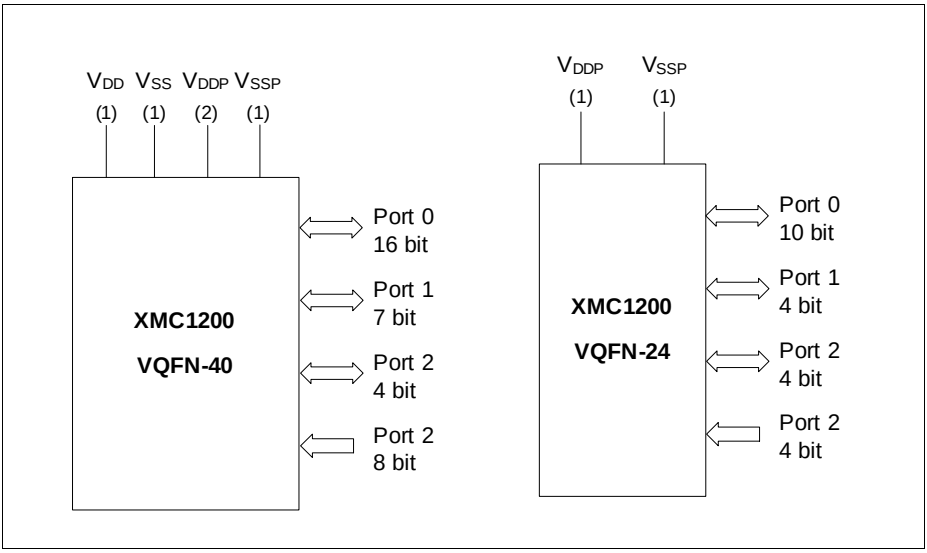

Figure 3 XMC1200 Logic Symbol for VQFN-24 and VQFN-40

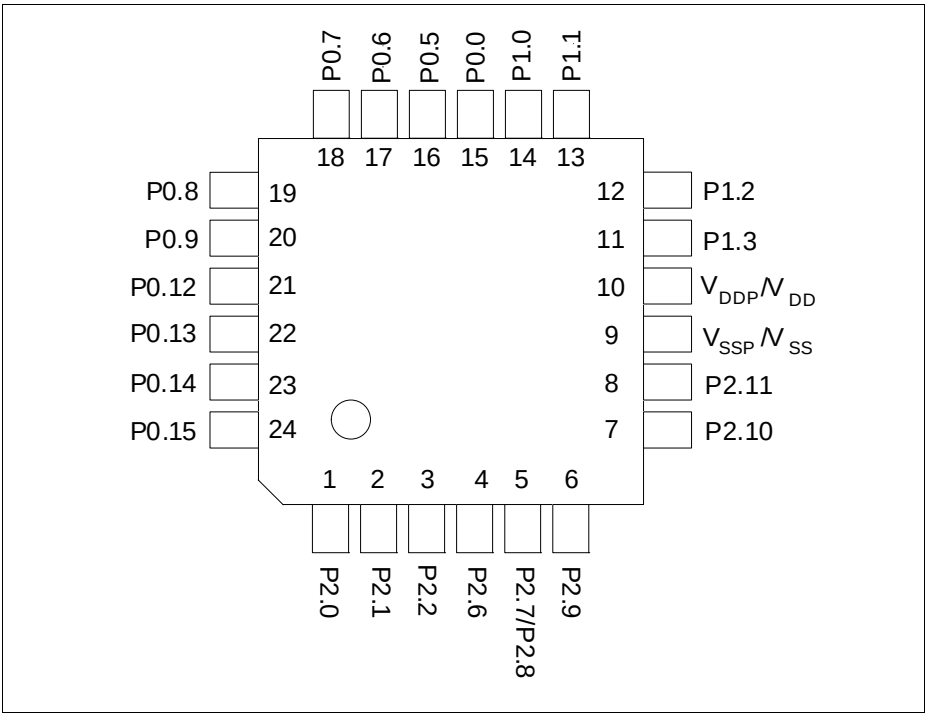

Figure 7 XMC1200 PG-VQFN-24 Pin Configuration (top view)

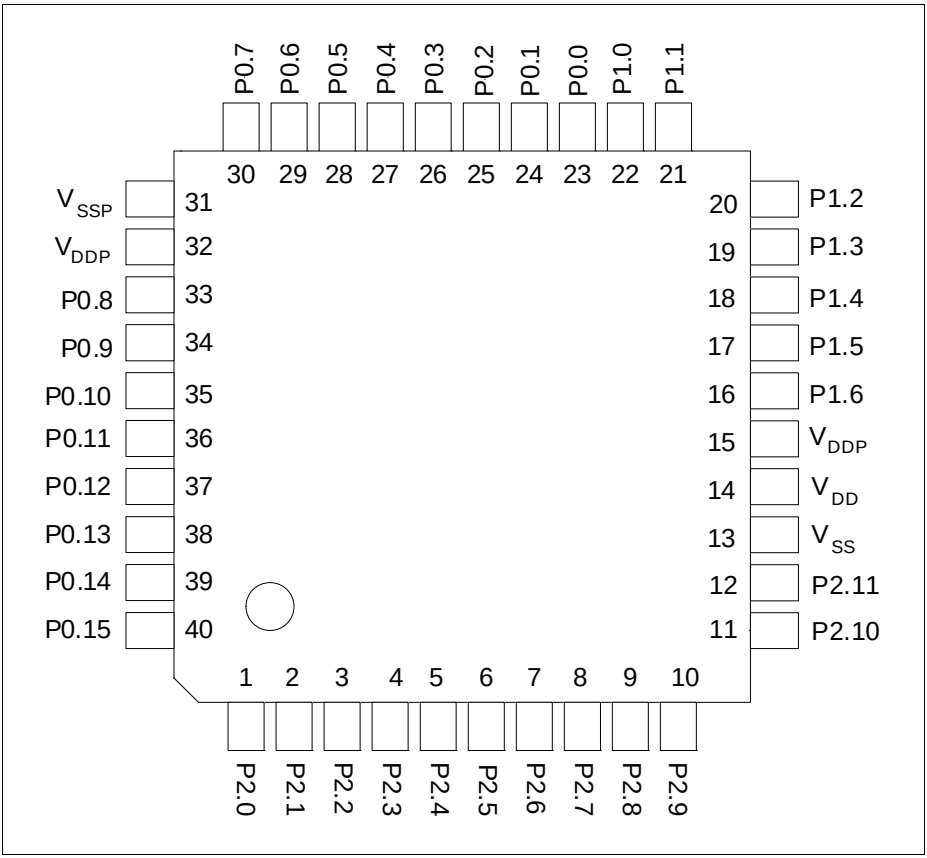

Figure 8 XMC1200 PG-VQFN-40 Pin Configuration (top view)

Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P0.7	30	24	17	18	10	STD_INOUT	
P0.8	33	27	18	19	11	STD_INOUT	
P0.9	34	28	19	20	12	STD_INOUT	
P0.10	35	29	20	-	-	STD_INOUT	
P0.11	36	30	-	-	-	STD_INOUT	
P0.12	37	31	21	21	-	STD_INOUT	
P0.13	38	32	22	22	-	STD_INOUT	
P0.14	39	33	23	23	13	STD_INOUT	
P0.15	40	34	24	24	14	STD_INOUT	
P1.0	22	16	12	14	-	High Current	
P1.1	21	15	11	13	-	High Current	
P1.2	20	14	10	12	-	High Current	
P1.3	19	13	9	11	-	High Current	
P1.4	18	12	-	-	-	High Current	
P1.5	17	11	-	-	-	High Current	
P1.6	16	-	-	-	-	STD_INOUT	
P2.0	1	35	25	1	15	STD_INOUT/AN	

Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
VSSP	31	25	-	-	-	Power	I/O port ground
VDDP	32	26	-	-	-	Power	I/O port supply
VSSP	Exp. Pad	-	-	Exp. Pad	-	Power	**Exposed Die Pad** The exposed die pad is connected internally to VSSP. For proper operation, it is mandatory to connect the exposed pad to the board ground. For thermal aspects, please refer to the Package and Reliability chapter.

Table 9 Port I/O Functions

Function	Outputs							Inputs							
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	Input	Input	Input	Input	Input	Input	Input	Input
P0.0	ERU0.PDOUT0	LEDTS0.LINE7	ERU0.GOUT0	CCU40.OUT0		USIC0_CH0.SELO0	USIC0_CH1.SELO0	BCCU0.TRAPINB	CCU40.IN0C			USIC0_CH0.DX2A	USIC0_CH1.DX2A		
P0.1	ERU0.PDOUT1	LEDTS0.LINE6	ERU0.GOUT1	CCU40.OUT1		BCCU0.OUT8	SCU.VDROP		CCU40.IN1C						
P0.2	ERU0.PDOUT2	LEDTS0.LINE5	ERU0.GOUT2	CCU40.OUT2		VADC0.EMUX02			CCU40.IN2C						
P0.3	ERU0.PDOUT3	LEDTS0.LINE4	ERU0.GOUT3	CCU40.OUT3		VADC0.EMUX01			CCU40.IN3C						
P0.4	BCCU0.OUT0	LEDTS0.LINE3	LEDTS0.COL3	CCU40.OUT1		VADC0.EMUX00	WWDT.SERVICE_OUT								
P0.5	BCCU0.OUT1	LEDTS0.LINE2	LEDTS0.COL2	CCU40.OUT0		ACMP2.OUT									
P0.6	BCCU0.OUT2	LEDTS0.LINE1	LEDTS0.COL1	CCU40.OUT0		USIC0_CH1.MCLKOUT	USIC0_CH1.DOUT0		CCU40.IN0B			USIC0_CH1.DX0C			
P0.7	BCCU0.OUT3	LEDTS0.LINE0	LEDTS0.COL0	CCU40.OUT1		USIC0_CH0.SCLKOUT	USIC0_CH1.DOUT0		CCU40.IN1B			USIC0_CH0.DX1C	USIC0_CH1.DX0D	USIC0_CH1.DX1C	
P0.8	BCCU0.OUT4	LEDTS1.LINE0	LEDTS0.COLA	CCU40.OUT2		USIC0_CH0.SCLKOUT	USIC0_CH1.SCLKOUT		CCU40.IN2B			USIC0_CH0.DX1B	USIC0_CH1.DX1B		
P0.9	BCCU0.OUT5	LEDTS1.LINE1	LEDTS0.COL6	CCU40.OUT3		USIC0_CH0.SELO0	USIC0_CH1.SELO0		CCU40.IN3B			USIC0_CH0.DX2B	USIC0_CH1.DX2B		
P0.10	BCCU0.OUT6	LEDTS1.LINE2	LEDTS0.COL5	ACMP0.OUT		USIC0_CH0.SELO1	USIC0_CH1.SELO1					USIC0_CH0.DX2C	USIC0_CH1.DX2C		
P0.11	BCCU0.OUT7	LEDTS1.LINE3	LEDTS0.COL4	USIC0_CH0.MCLKOUT		USIC0_CH0.SELO2	USIC0_CH1.SELO2					USIC0_CH0.DX2D	USIC0_CH1.DX2D		
P0.12	BCCU0.OUT6	LEDTS1.LINE4	LEDTS0.COL3	LEDTS1.COL3		USIC0_CH0.SELO3		BCCU0.TRAPINA	CCU40.IN0A	CCU40.IN1A	CCU40.IN2A	CCU40.IN3A	USIC0_CH0.DX2E		
P0.13	WWDT.SERVICE_OUT	LEDTS1.LINE5	LEDTS0.COL2	LEDTS1.COL2		USIC0_CH0.SELO4						USIC0_CH0.DX2F			
P0.14	BCCU0.OUT7	LEDTS1.LINE6	LEDTS0.COL1	LEDTS1.COL1		USIC0_CH0.DOUT0	USIC0_CH0.SCLKOUT					USIC0_CH0.DX0A	USIC0_CH0.DX1A		

Table 13 PN-Junction Characterisitics for positive Overload

Pad Type	I_{OV} = 5 mA, T_J = -40 °C	I_{OV} = 5 mA, T_J = 115 °C
Standard, High-current, AN/DIG_IN	$V_{IN} = V_{DDP} + 0.5$ V	$V_{IN} = V_{DDP} + 0.5$ V

Table 14 PN-Junction Characterisitics for negative Overload

Pad Type	I_{OV} = 5 mA, T_J = -40 °C	I_{OV} = 5 mA, T_J = 115 °C
Standard, High-current, AN/DIG_IN	$V_{IN} = V_{SS} - 0.5$ V	$V_{IN} = V_{SS} - 0.5$ V

3.1.4 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation and reliability of the XMC1200. All parameters specified in the following tables refer to these operating conditions, unless noted otherwise.

Table 15 Operating Conditions Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Ambient Temperature	T_A SR	-40	–	85	°C	Temp. Range F
		-40	–	105	°C	Temp. Range X
Digital supply voltage[1)]	V_{DDP} SR	1.8	–	5.5	V	
MCLK Frequency	f_{MCLK} CC	–	–	33.2	MHz	CPU clock
PCLK Frequency	f_{PCLK} CC	–	–	66.4	MHz	Peripherals clock
Short circuit current of digital outputs	I_{SC} SR	-5	–	5	mA	
Absolute sum of short circuit currents of the device	ΣI_{SC_D} SR	–	–	25	mA	

1) See also the Supply Monitoring thresholds, **Chapter 3.3.2**.

3.2 DC Parameters

3.2.1 Input/Output Characteristics

Table 16 provides the characteristics of the input/output pins of the XMC1200.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Note: Unless otherwise stated, input DC and AC characteristics, including peripheral timings, assume that the input pads operate with the standard hysteresis.

Table 16 Input/Output Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Output low voltage on port pins (with standard pads)	V_{OLP}	CC	–	1.0	V	I_{OL} = 11 mA (5 V) I_{OL} = 7 mA (3.3 V)
			–	0.4	V	I_{OL} = 5 mA (5 V) I_{OL} = 3.5 mA (3.3 V)
Output low voltage on high current pads	V_{OLP1}	CC	–	1.0	V	I_{OL} = 50 mA (5 V) I_{OL} = 25 mA (3.3 V)
			–	0.32	V	I_{OL} = 10 mA (5 V)
			–	0.4	V	I_{OL} = 5 mA (3.3 V)
Output high voltage on port pins (with standard pads)	V_{OHP}	CC	V_{DDP} - 1.0	–	V	I_{OH} = -10 mA (5 V) I_{OH} = -7 mA (3.3 V)
			V_{DDP} - 0.4	–	V	I_{OH} = -4.5 mA (5 V) I_{OH} = -2.5 mA (3.3 V)
Output high voltage on high current pads	V_{OHP1}	CC	V_{DDP} - 0.32	–	V	I_{OH} = -6 mA (5 V)
			V_{DDP} - 1.0	–	V	I_{OH} = -8 mA (3.3 V)
			V_{DDP} - 0.4	–	V	I_{OH} = -4 mA (3.3 V)
Input low voltage on port pins (Standard Hysteresis)	V_{ILPS}	SR	–	0.19 × V_{DDP}	V	CMOS Mode (5 V, 3.3 V & 2.2 V)
Input high voltage on port pins (Standard Hysteresis)	V_{IHPS}	SR	0.7 × V_{DDP}	–	V	CMOS Mode (5 V, 3.3 V & 2.2 V)

Table 17 ADC Characteristics (Operating Conditions apply)[1] (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum sample rate in 8-bit mode [3]	f_{C8} CC	–	–	f_{ADC} / 38.5	–	1 sample pending
		–	–	f_{ADC} / 54.5	–	2 samples pending
RMS noise [4]	EN_{RMS} CC	–	1.5	–	LSB 12	DC input, V_{DD} = 5.0 V, V_{AIN} = 2.5 V, 25°C
DNL error	EA_{DNL} CC	–	±2.0	–	LSB 12	
INL error	EA_{INL} CC	–	±4.0	–	LSB 12	
Gain error with external reference	EA_{GAIN} CC	–	±0.5	–	%	SHSCFG.AREF = 00_B (calibrated)
Gain error with internal reference [5]	EA_{GAIN} CC	–	±3.6	–	%	SHSCFG.AREF = $1X_B$ (calibrated), -40°C - 105°C
		–	±2.0	–	%	SHSCFG.AREF = $1X_B$ (calibrated), 0°C - 85°C
Offset error	EA_{OFF} CC	–	±8.0	–	mV	Calibrated, V_{DD} = 5.0 V

1) The parameters are defined for ADC clock frequency f_{SH} = 32MHz, SHSCFG.DIVS = 0000_B. Usage of any other frequencies may affect the ADC performance.

2) No pending samples assumed, excluding sampling time and calibration.

3) Includes synchronization and calibration (average of gain and offset calibration).

4) This parameter can also be defined as an SNR value: SNR[dB] = 20 × log(A_{MAXeff} / N_{RMS}).
With $A_{MAXeff} = 2^N / 2$, SNR[dB] = 20 × log (2048 / N_{RMS}) [N = 12].
N_{RMS} = 1.5 LSB12, therefore, equals SNR = 20 × log (2048 / 1.5) = 62.7 dB.

5) Includes error from the reference voltage.

3.2.3 Out of Range Comparator (ORC) Characteristics

The Out-of-Range Comparator (ORC) triggers on analog input voltages (V_{AIN}) above the V_{DDP} on selected input pins (ORCx.AIN) and generates a service request trigger (ORCx.OUT).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 18 Out of Range Comparator (ORC) Characteristics (Operating Conditions apply; V_{DDP} = 3.0 V - 5.5 V; C_L = 0.25 pF)

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
DC Switching Level	V_{ODC} C C		54	–	183	mV	$V_{AIN} \geq V_{DDP} + V_{ODC}$
Hysteresis	V_{OHYS}	CC	15	–	54	mV	
Always detected Overvoltage Pulse	t_{OPDD}	CC	103	–	–	ns	$V_{AIN} \geq V_{DDP}$ + 150 mV
			88	–	–	ns	$V_{AIN} \geq V_{DDP}$ + 350 mV
Never detected Overvoltage Pulse	t_{OPDN}	CC	–	–	21	ns	$V_{AIN} \geq V_{DDP}$ + 150 mV
			–	–	11	ns	$V_{AIN} \geq V_{DDP}$ + 350 mV
Detection Delay of a persistent Overvoltage	t_{ODD}	CC	39	–	132	ns	$V_{AIN} \geq V_{DDP}$ + 150 mV
			31	–	121	ns	$V_{AIN} \geq V_{DDP}$ + 350 mV
Release Delay	t_{ORD}	CC	44	–	240	ns	$V_{AIN} \leq V_{DDP}$; V_{DDP} = 5 V
			57	–	340	ns	$V_{AIN} \leq V_{DDP}$; V_{DDP} = 3.3 V
Enable Delay	t_{OED}	CC	–	–	300	ns	ORCCTRL.ENORCx = 1

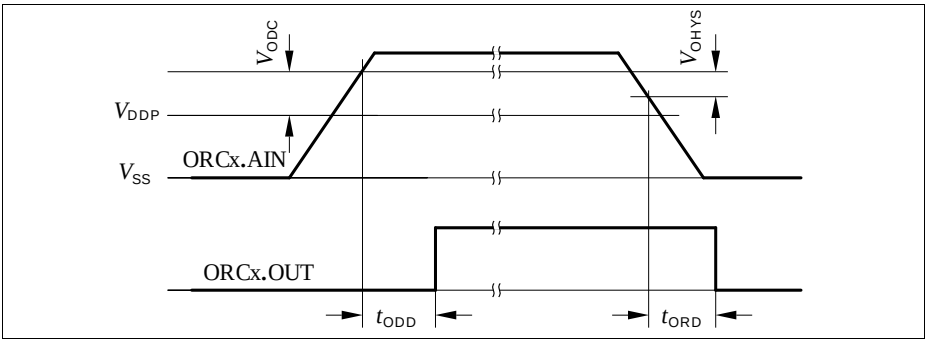

Figure 12 ORCx.OUT Trigger Generation

3.2.7 Flash Memory Parameters

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 Flash Memory Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Erase Time per page / sector	t_{ERASE} CC	6.8	7.1	7.6	ms	
Program time per block	t_{PSER} CC	102	152	204	µs	
Wake-Up time	t_{WU} CC	–	32.2	–	µs	
Read time per word	t_a CC	–	50	–	ns	
Data Retention Time	t_{RET} CC	10	–	–	years	Max. 100 erase / program cycles
Flash Wait States [1]	$N_{WSFLASH}$ CC	0	0	0		f_{MCLK} = 8 MHz
		0	1	1		f_{MCLK} = 16 MHz
		1	1.3	2		f_{MCLK} = 32 MHz
Fixed Flash Wait States configured in bit NVM_NVMCONF.WS	$N_{FWSFLASH}$ SR	0	0	1		NVM_CONFIG1. FIXWS = 1_B, $f_{MCLK} \leq$ 16 MHz
		1	1	1		NVM_CONFIG1. FIXWS = 1_B, 16 MHz < $f_{MCLK} \leq$ 32 MHz
Erase Cycles	N_{ECYC} CC	–	–	$5*10^4$	cycles	Sum of page and sector erase cycles
Total Erase Cycles	N_{TECYC} CC	–	–	$2*10^6$	cycles	

1) Flash wait states are automatically inserted by the Flash module during memory read when needed. Typical values are calculated from the execution of the Dhrystone benchmark program.

3.3.4 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 27 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	–	500000	ns	–
SWDCLK low time	t_2 SR	50	–	500000	ns	–
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	–	–	ns	–
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	–	–	ns	–
SWDIO output valid time after SWDCLK rising edge	t_5 CC	–	–	68	ns	C_L = 50 pF
		–	–	62	ns	C_L = 30 pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	–	–	ns	

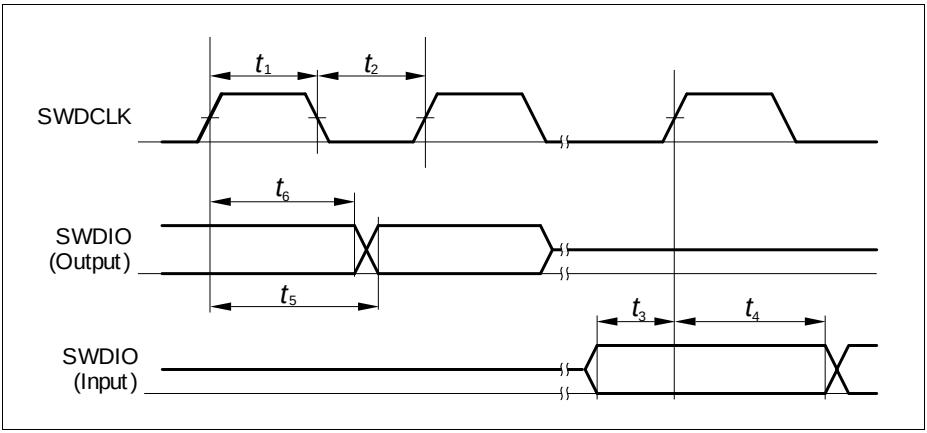

Figure 21 SWD Timing

3.3.5 SPD Timing Requirements

The optimum SPD decision time between 0_B and 1_B is 0.75 µs. With this value the system has maximum robustness against frequency deviations of the sampling clock on tool and on device side. However it is not always possible to exactly match this value with the given constraints for the sample clock. For instance for a oversampling rate of 4, the sample clock will be 8 MHz and in this case the closest possible effective decision time is 5.5 clock cycles (0.69 µs).

Table 28 Optimum Number of Sample Clocks for SPD

Sample Freq.	Sampling Factor	Sample Clocks 0_B	Sample Clocks 1_B	Effective Decision Time[1)]	Remark
8 MHz	4	1 to 5	6 to 12	0.69 µs	The other closest option (0.81 µs) for the effective decision time is less robust.

1) Nominal sample frequency period multiplied with 0.5 + (max. number of 0_B sample clocks)

For a balanced distribution of the timing robustness of SPD between tool and device, the timing requirements for the tool are:

- Frequency deviation of the sample clock is +/- 5%
- Effective decision time is between 0.69 µs and 0.75 µs (calculated with nominal sample frequency)

Table 32 USIC IIC Fast Mode Timing[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1*C_b [2)]	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1*C_b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximalely 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

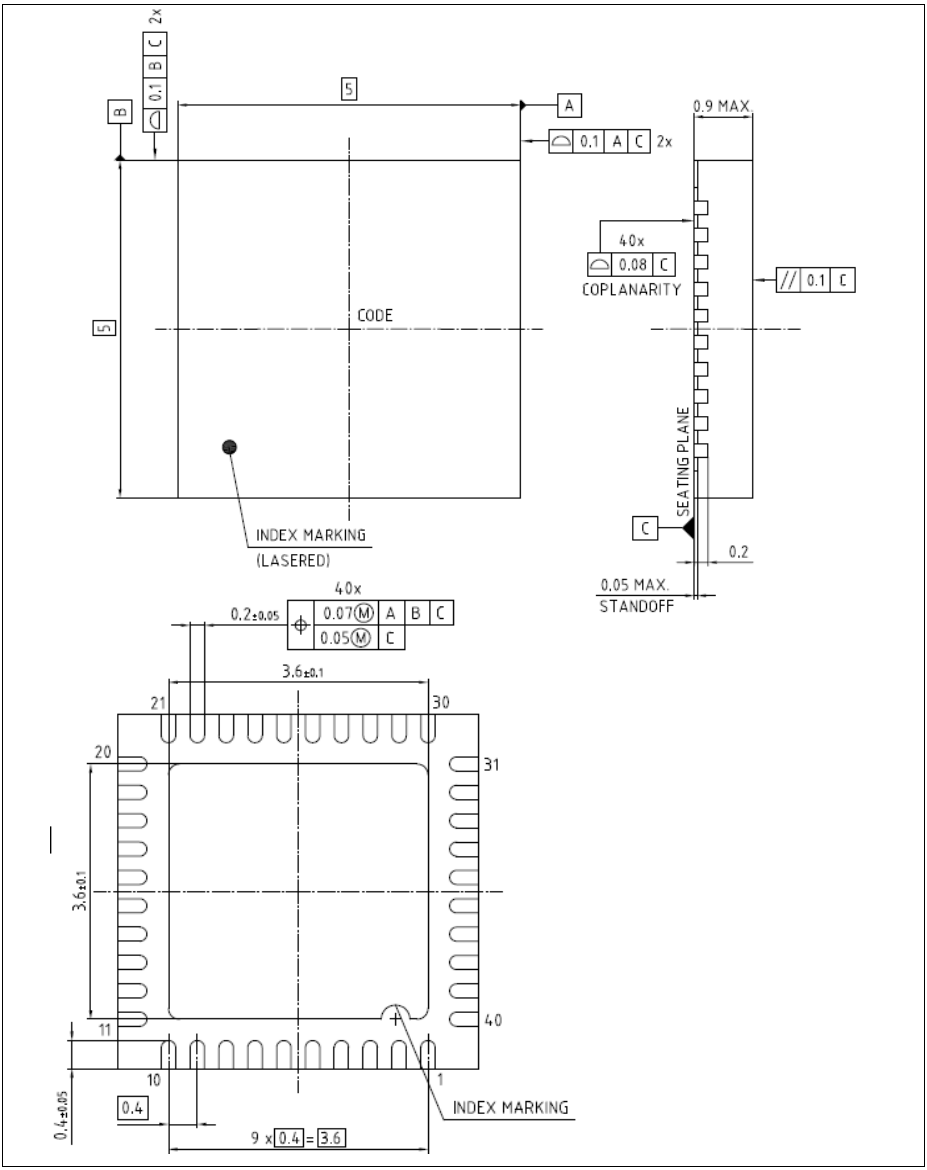

Figure 30 PG-VQFN-40-13

All dimensions in mm.

5 Quality Declaration

Table 36 shows the characteristics of the quality parameters in the XMC1200.

Table 36 Quality Parameters

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	V_{HBM} SR	-	2000	V	Conforming to EIA/JESD22-A114-B
ESD susceptibility according to Charged Device Model (CDM) pins	V_{CDM} SR	-	500	V	Conforming to JESD22-C101-C
Moisture sensitivity level	MSL CC	-	3	-	JEDEC J-STD-020D
Soldering temperature	T_{SDR} SR	-	260	°C	Profile according to JEDEC J-STD-020D